

AEC-Q100

Reliability Test Report

QR-TC-18

Name of Client: Shanghai Fudan Microelectronics Group Co., Ltd
Address of Client: Building 4, 127 Guotai Road Shanghai 200433, China
Sample Name: FM33LE023A/FM33LE013A
Sample Information: W5B36J1G、W5B38JAG、W5B40JEG
Date of Receipt: 2022/11/24
Test Method: AEC Q100-Rev-H-2014 Grade 1: -40°C ~ +125°C
Test Period: 2022/11/25 ~ 2023/01/13
Test Result: This is to certify that the above-mentioned product(s) complies with the standard & technical requirements of "AEC-Q100-Rev-H: 2014 Failure mechanism-based stress test qualification for integrated circuits". The assessment has been completed under the AEC-Q100 Grade 1, which meet the demands of the above technical standards and product specifications. The sample is qualified for this test. For further details, please refer to Test Result Summary.

Prepared by Chen Chao **Checked by** Xu Yongjun **Authorized by** Ma XiChun

(signature) Chen Chao (signature) Xu Yongjun (signature) Ma XiChun

Wuxi CMC electronics Co., Ltd
Issued Date: 2023/01/13

The test results presented in this report relate to particular samples submitted for testing only. The report is invalid without an authorized signature and special stamp. The report shall not be partially reproduced without the written approval of CMC. Any objection shall be raised within 30 days from the receipt of the report.

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